



CYPRESS

CY7C187

## 64K x 1 Static RAM

### Features

- **High speed**  
— 15 ns
- **CMOS for optimum speed/power**
- **Low active power**  
— 495 mW
- **Low standby power**  
— 220 mW
- **TTL compatible inputs and outputs**
- **Automatic power-down when deselected**

### Functional Description

The CY7C187 is a high-performance CMOS static RAM organized as 65,536 words x 1 bit. Easy memory expansion is pro-

vided by an active LOW Chip Enable ( $\overline{CE}$ ) and three-state drivers. The CY7C187 has an automatic power-down feature, reducing the power consumption by 56% when deselected.

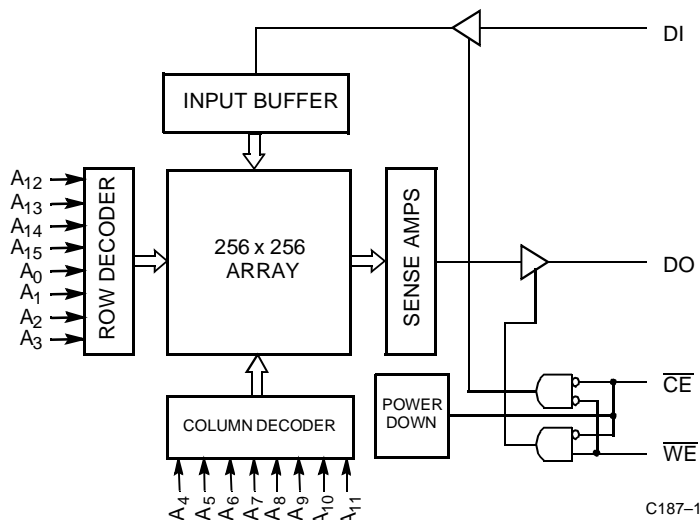
Writing to the device is accomplished when the Chip Enable ( $\overline{CE}$ ) and Write Enable ( $\overline{WE}$ ) inputs are both LOW. Data on the input pin ( $D_{IN}$ ) is written into the memory location specified on the address pins ( $A_0$  through  $A_{15}$ ).

Reading the device is accomplished by taking the Chip Enable ( $\overline{CE}$ ) LOW, while Write Enable ( $\overline{WE}$ ) remains HIGH. Under these conditions, the contents of the memory location specified on the address pin will appear on the data output ( $D_{OUT}$ ) pin.

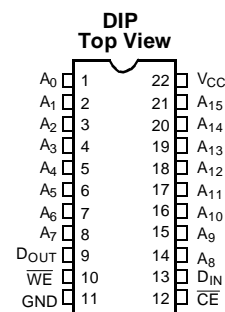
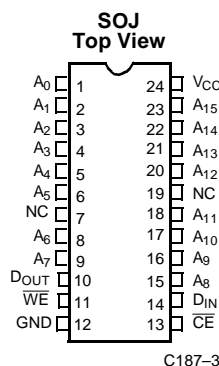
The output pin stays in high-impedance state when Chip Enable ( $\overline{CE}$ ) is HIGH or Write Enable ( $\overline{WE}$ ) is LOW.

The CY7C187 utilizes a die coat to insure alpha immunity.

### Logic Block Diagram



### Pin Configurations



### Selection Guide<sup>[1]</sup>

	7C187-15	7C187-20	7C187-25	7C187-35
Maximum Access Time (ns)	15	20	25	35
Maximum Operating Current (mA)	90	80	70	70
Maximum Standby Current (mA)	40/20	40/20	20/20	20/20

#### Note:

1. For military specifications, see the CY7C187A datasheet.

## Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... -65°C to +150°C

Ambient Temperature with  
Power Applied ..... -55°C to +125°C

Supply Voltage to Ground Potential  
(Pin 22 to Pin 11) ..... -0.5V to +7.0V

DC Voltage Applied to Outputs  
in High Z State<sup>[2]</sup> ..... -0.5V to +7.0V

DC Input Voltage<sup>[2]</sup> ..... -0.5V to +7.0V

Output Current into Outputs (LOW) ..... 20 mA

Static Discharge Voltage ..... >2001V  
(per MIL-STD-883, Method 3015)

Latch-Up Current ..... >200 mA

## Operating Range

Range	Ambient Temperature	V <sub>CC</sub>
Commercial	0°C to +70°C	5V ± 10%

## Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions	7C187-15		7C187-20		7C187-25, 35		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 12.0 mA		0.4		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	V
V <sub>IL</sub>	Input LOW Voltage <sup>[2]</sup>		-0.5	0.8	-0.5	0.8	-0.5	0.8	V
I <sub>IX</sub>	Input Load Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	-5	+5	-5	+5	-5	+5	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>CC</sub> , Output Disabled	-5	+5	-5	+5	-5	+5	μA
I <sub>OS</sub>	Output Short Circuit Current <sup>[3]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = GND		-350		-350		-350	mA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA		90		80		70	mA
I <sub>SB1</sub>	Automatic $\overline{CE}$ Power-Down Current <sup>[4]</sup>	Max. V <sub>CC</sub> , $\overline{CE} \geq V_{IH}$		40		40		20	mA
I <sub>SB2</sub>	Automatic $\overline{CE}$ Power-Down Current	Max. V <sub>CC</sub> , $\overline{CE} \geq V_{CC} - 0.3V$ , V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.3V or V <sub>IN</sub> ≤ 0.3V		20		20		20	mA

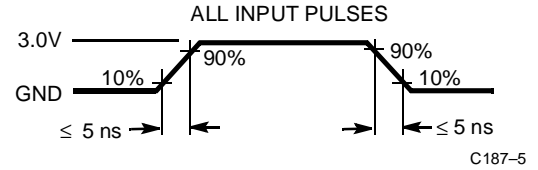
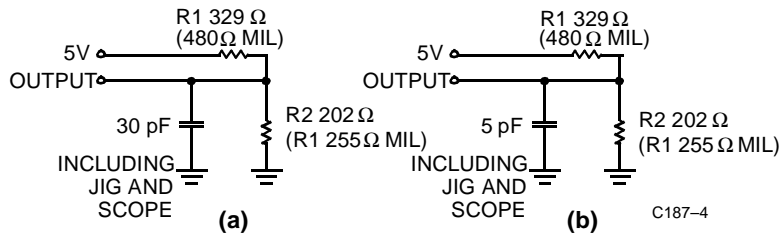
## Capacitance<sup>[5]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	T <sub>A</sub> = 25°C, f = 1 MHz, V <sub>CC</sub> = 5.0V	10	pF
C <sub>OUT</sub>	Output Capacitance		10	pF

### Notes:

- V<sub>IL</sub> (min.) = -3.0V for pulse durations less than 30 ns.
- Not more than 1 output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds.
- A pull-up resistor to V<sub>CC</sub> on the  $\overline{CE}$  input is required to keep the device deselected during V<sub>CC</sub> power-up, otherwise I<sub>SB</sub> will exceed values given.
- Tested initially and after any design or process changes that may affect these parameters.

## AC Test Loads and Waveforms



Equivalent to: THÉVENIN EQUIVALENT



## Switching Characteristics Over the Operating Range<sup>[6]</sup>

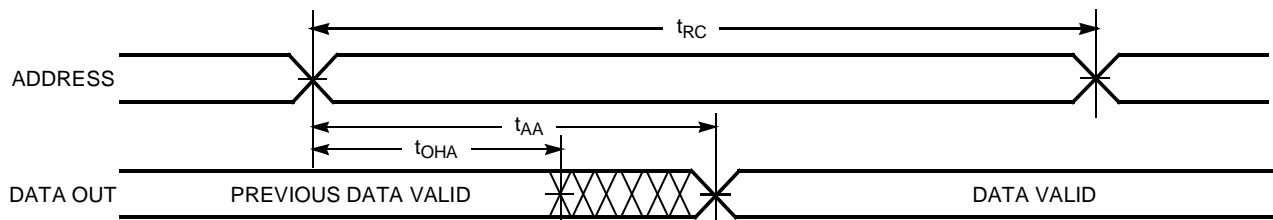
Parameter	Description	7C187-15		7C187-20		Unit
		Min.	Max.	Min.	Max.	
READ CYCLE						
t <sub>RC</sub>	Read Cycle Time	15		20		ns
t <sub>AA</sub>	Address to Data Valid		15		20	ns
t <sub>OHA</sub>	Output Hold from Address Change	3		5		ns
t <sub>ACE</sub>	$\overline{CE}$ LOW to Data Valid		15		20	ns
t <sub>LZCE</sub>	$\overline{CE}$ LOW to Low Z <sup>[7]</sup>	3		5		ns
t <sub>HZCE</sub>	$\overline{CE}$ HIGH to High Z <sup>[7, 8]</sup>		8		8	ns
t <sub>PU</sub>	$\overline{CE}$ LOW to Power Up	0		0		ns
t <sub>PD</sub>	$\overline{CE}$ HIGH to Power Down		15		20	ns
WRITE CYCLE <sup>[9]</sup>						
t <sub>WC</sub>	Write Cycle Time	15		20		ns
t <sub>SCE</sub>	$\overline{CE}$ LOW to Write End	12		15		ns
t <sub>AW</sub>	Address Set-Up to Write End	12		15		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	$\overline{WE}$ Pulse Width	12		15		ns
t <sub>SD</sub>	Data Set-Up to Write End	10		10		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>LZWE</sub>	$\overline{WE}$ HIGH to Low Z	5		5		ns
t <sub>HZWE</sub>	$\overline{WE}$ LOW to High Z <sup>[8]</sup>		7		7	ns

### Notes:

- Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified  $I_{OL}/I_{OH}$  and 30-pF load capacitance.
- At any given temperature and voltage condition,  $t_{HZCE}$  is less than  $t_{LZCE}$  for any given device.
- $t_{HZCE}$  and  $t_{HZWE}$  are specified with  $C_L = 5$  pF as in part (b) of AC Test Loads. Transition is measured  $\pm 500$  mV from steady-state voltage.
- The internal write time of the memory is defined by the overlap of  $\overline{CE}$  LOW and  $\overline{WE}$  LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

**Switching Characteristics** Over the Operating Range<sup>[6]</sup> (continued)

Parameters	Description	7C187-25		7C187-35		Units
		Min.	Max.	Min.	Max.	
READ CYCLE						
t <sub>RC</sub>	Read Cycle Time	25		35		ns
t <sub>AA</sub>	Address to Data Valid		25		35	ns
t <sub>OHA</sub>	Output Hold from Address Change	5		5		ns
t <sub>ACE</sub>	$\overline{CE}$ LOW to Data Valid		25		35	ns
t <sub>LZCE</sub>	$\overline{CE}$ LOW to Low Z <sup>[7]</sup>	5		5		ns
t <sub>HZCE</sub>	$\overline{CE}$ HIGH to High Z <sup>[7, 8]</sup>		10		15	ns
t <sub>PU</sub>	$\overline{CE}$ LOW to Power Up	0		0		ns
t <sub>PD</sub>	$\overline{CE}$ HIGH to Power Down		20		20	ns
WRITE CYCLE <sup>[9]</sup>						
t <sub>WC</sub>	Write Cycle Time	20		25		ns
t <sub>SCE</sub>	$\overline{CE}$ LOW to Write End	20		25		ns
t <sub>AW</sub>	Address Set-Up to Write End	20		25		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		ns
t <sub>PWE</sub>	$\overline{WE}$ Pulse Width	15		20		ns
t <sub>SD</sub>	Data Set-Up to Write End	10		15		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		ns
t <sub>LZWE</sub>	$\overline{WE}$ HIGH to Low	5		5		ns
t <sub>HZWE</sub>	$\overline{WE}$ LOW to High Z <sup>[8]</sup>		7		10	ns

**Switching Waveforms**
**Read Cycle No. 1<sup>[10, 11]</sup>**


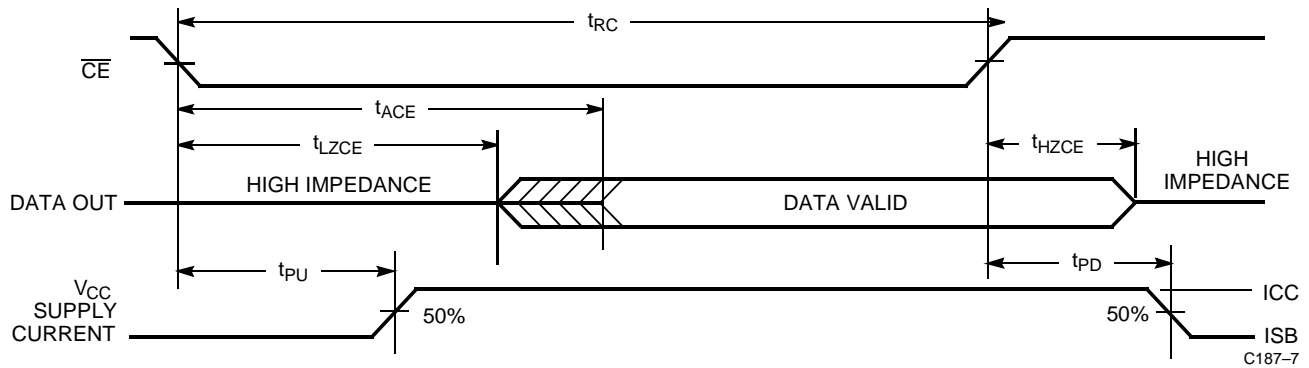
C187-6

**Notes:**

10.  $\overline{WE}$  is HIGH for read cycle.
11. Device is continuously selected,  $\overline{CE} = V_{IL}$ .

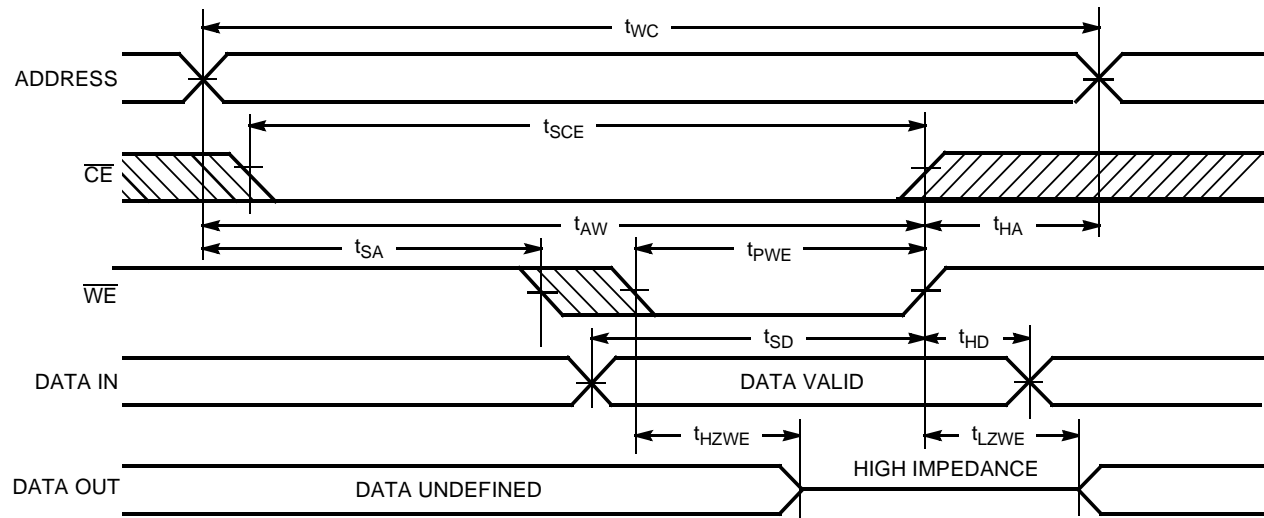
## Switching Waveforms

### Read Cycle No. 2<sup>[10, 12]</sup>



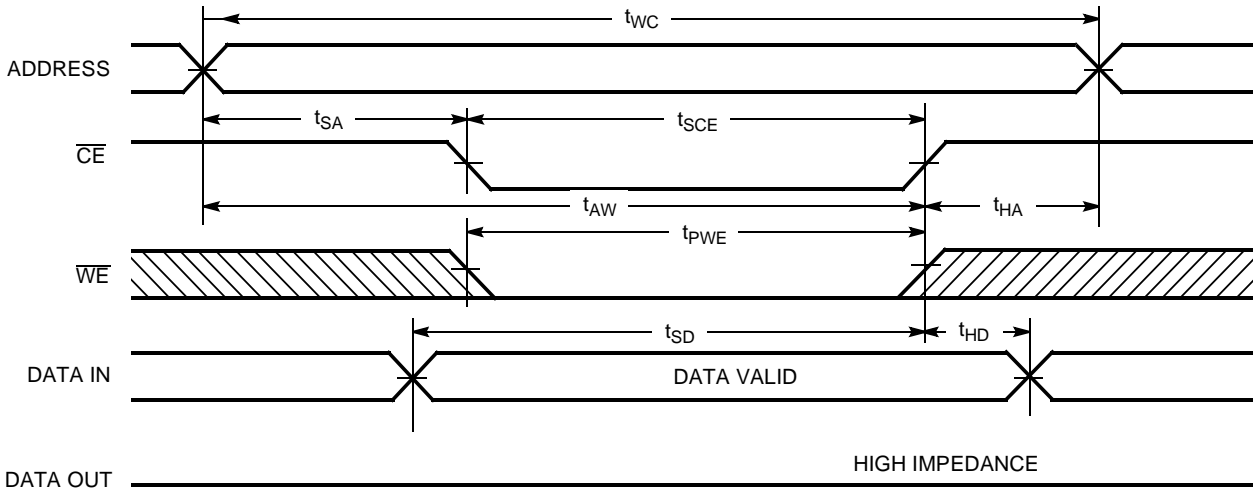
C187-7

### Write Cycle No. 1 ( $\overline{WE}$ Controlled)<sup>[11]</sup>



C187-8

### Write Cycle No. 2 ( $\overline{CE}$ Controlled)<sup>[11, 13]</sup>

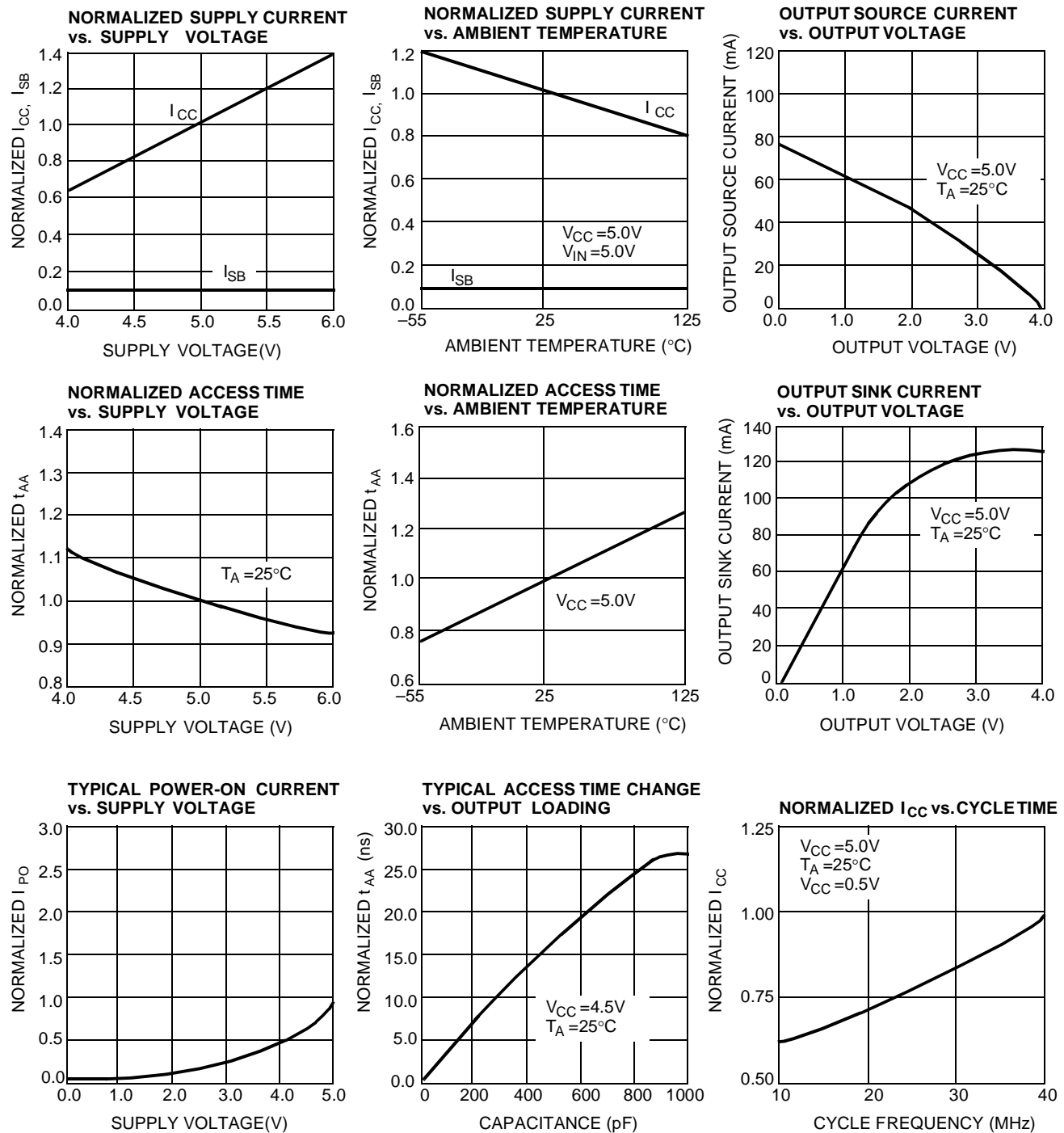


C187-9

#### Notes:

12. Address valid prior to or coincident with  $\overline{CE}$  transition LOW.
13. If  $\overline{CE}$  goes HIGH simultaneously with  $\overline{WE}$  HIGH, the output remains in a high-impedance state.

## Typical DC and AC Characteristics



**Address Designators**

Address Name	Address Function	Pin Number
A0	X3	1
A1	X4	2
A2	X5	3
A3	X6	4
A4	X7	5
A5	Y7	6
A6	Y6	7
A7	Y2	8
A8	Y3	14
A9	Y1	15
A10	Y0	16
A11	Y4	17
A12	Y5	18
A13	X0	19
A14	X1	20
A15	X2	21

**Truth Table**

$\overline{CE}$	$\overline{WE}$	Input/Output	Mode
H	X	High Z	Deselect/Power-Down
L	H	Data Out	Read
L	L	Data In	Write

**Ordering Information<sup>[14]</sup>**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C187-15PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-15VC	V13	24-Lead Molded SOJ	
20	CY7C187-20PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-20VC	V13	24-Lead Molded SOJ	
25	CY7C187-25PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-25VC	V13	24-Lead Molded SOJ	
35	CY7C187-35PC	P9	22-Lead (300-Mil) Molded DIP	Commercial
	CY7C187-35VC	V13	24-Lead Molded SOJ	

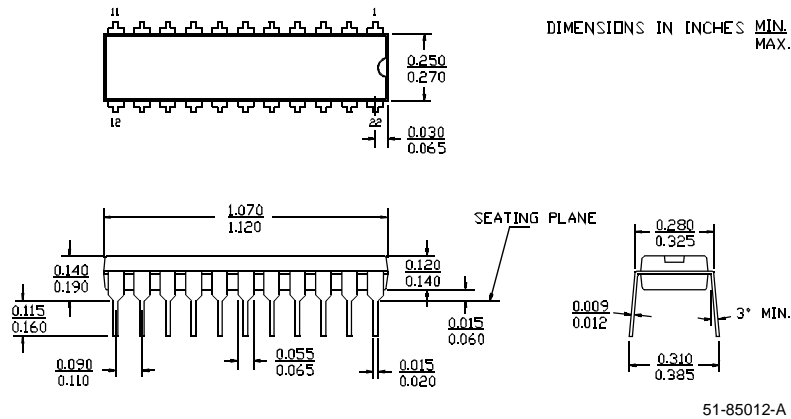
**Note:**

14. For military variations, see the CY7C187A datasheet.

Document #: 38-00038-K

## Package Diagrams

### 22-Lead (300-Mil) Molded DIP P9



### 24-Lead (300-Mil) Molded SOJ V13

